

AUIRF2805S AUIRF2805L

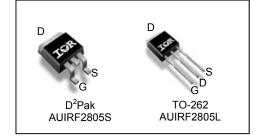
Features

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and wide variety of other applications.

	V _{DSS}	55V
	R _{DS(on)} typ.	3.9mΩ
)	max.	4.7mΩ
	I _D	135A©



G	D	S
Gate	Drain	Source

Bees nort number	Dookogo Turoo	Standard Pack		Orderable Part Number	
Base part number	Package Type	Form	Quantity	Orderable Part Number	
AUIRF2805L	TO-262	Tube	50	AUIRF2805L	
AUIRF2805S	D ² -Pak	Tube	50	AUIRF2805S	
AUIRF20055	D-Fak	Tape and Reel Left	800	AUIRF2805STRL	

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	135©	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	96©	A
I _{DM}	Pulsed Drain Current ①	700	
P _D @T _C = 25°C	Maximum Power Dissipation	200	W
	Linear Derating Factor	1.3	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) 2	380	
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ®	920	mJ
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	A
E _{AR}	Repetitive Avalanche Energy Ø		mJ
dv/dt	Pead Diode Recovery dv/dt3	2.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
R _{θJC}	Junction-to-Case		0.75	°C () ()
R _{0JA}	Junction-to-Ambient (PCB Mount, steady state)		40	°C/W

HEXFET® is a registered trademark of Infineon.

*Qualification standards can be found at www.infineon.com



AUIRF2805S/L

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	V _{GS} = 0V, I _D = 250µA
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temp. Coefficient		0.06		V/°C	Reference to 25°C, I_D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.9	4.7	mΩ	V _{GS} = 10V, I _D = 104A ④
V _{GS(th)}	Gate Threshold Voltage	2.0	_	4.0	V	V _{DS} = V _{GS} , I _D = 250μA
gfs	Forward Trans conductance	91			S	V _{DS} = 25V, I _D = 104A
1	Drain-to-Source Leakage Current			20	μA	V _{DS} =55 V, V _{GS} = 0V
IDSS	Drain-to-Source Leakage Current			250	μΑ	V _{DS} =44V,V _{GS} = 0V,T _J =150°C
1	Gate-to-Source Forward Leakage			200	n A	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-200	nA	V _{GS} = -20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Devenueter	N/1:	T	Max	11	Conditions
Diode Char	acteristics					
C _{oss eff.}	Effective Output Capacitance		1600			V_{GS} = 0V, V_{DS} = 0V to 44V
C _{oss}	Output Capacitance		860			$V_{GS} = 0V, V_{DS} = 44V f = 1.0MHz$
C _{oss}	Output Capacitance		6470		pi	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
C _{rss}	Reverse Transfer Capacitance		210		pF	<i>f</i> = 1.0MHz, See Fig. 5
C _{oss}	Output Capacitance		1190			V _{DS} = 25V
C _{iss}	Input Capacitance		5110			V _{GS} = 0V
Ls	Internal Source Inductance		7.5		nH	from package
L _D	Internal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
t _f	Fall Time		110			V _{GS} = 10V ④
t _{d(off)}	Turn-Off Delay Time		68		115	R _G = 2.5Ω
t _r	Rise Time		120		ns	I _D = 104A
t _{d(on)}	Turn-On Delay Time		14			$V_{DD} = 28V$
Q_{gd}	Gate-to-Drain Charge		52	78		V _{GS} = 10V④
Q_{gs}	Gate-to-Source Charge		38	57	nC	$V_{DS} = 44V$
Q _g	Total Gate Charge		150	230		I _D = 104A

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			175©		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			700		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_{J} = 25^{\circ}C, I_{S} = 104A, V_{GS} = 0V ④$
t _{rr}	Reverse Recovery Time		80	120	ns	T _J = 25°C ,I _F = 104A
Q _{rr}	Reverse Recovery Charge		290	430	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_{S}+L_{D}$)				

Notes:

- $\odot\;$ Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- \odot Limited by T_{Jmax}, starting T_J = 25°C, L = 0.08mH, R_G = 25 Ω , I_{AS} = 104A, V_{GS} =10V. (See Fig.12)
- ④ Pulse width \leq 400µs; duty cycle \leq 2%.
- \odot C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- © Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 75A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ⑦ Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- **(a)** This value determined from sample failure population, starting $T_J = 25^{\circ}C$, L = 0.08mH, $R_G = 25\Omega$, $I_{AS} = 104A$, $V_{GS} = 10V$.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994



1000

100

10

0.1

I_D, Drain-to-Source Current (A)

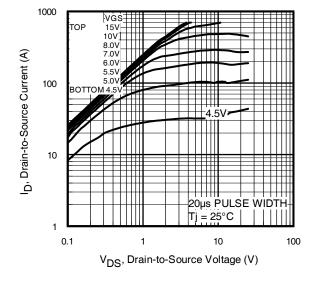
тор

VGS 15V 10V

8.0V 7.0V

6.0V 5.5V

5.0V BOTTOM 4.5V



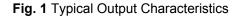


Fig. 2 Typical Output Characteristics

 V_{DS} , Drain-to-Source Voltage (V)

1

20µs PULSE WIDTH

100

Tj = 175°C

10

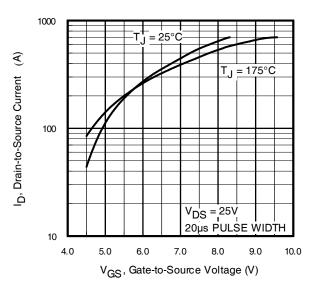


Fig. 3 Typical Transfer Characteristics

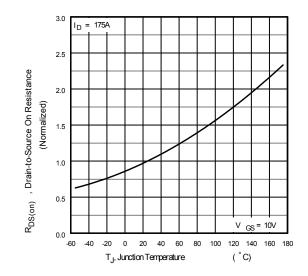
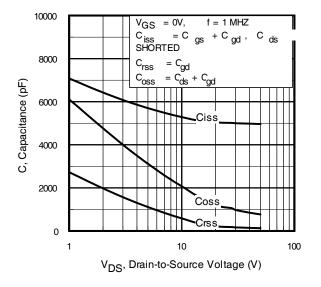
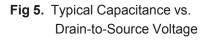


Fig. 4 Normalized On-Resistance vs. Temperature







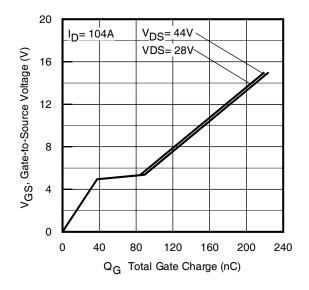


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

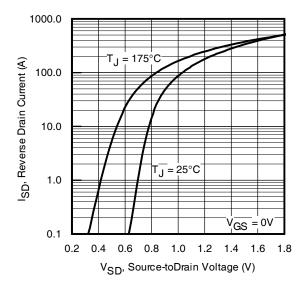


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

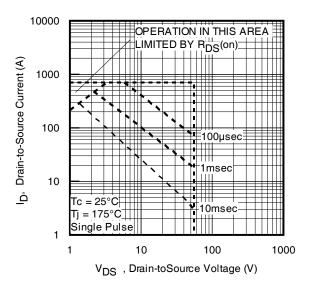
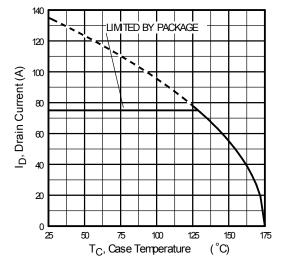


Fig 8. Maximum Safe Operating Area







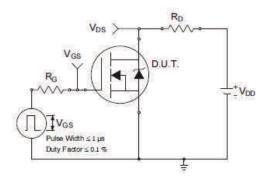


Fig 10a. Switching Time Test Circuit

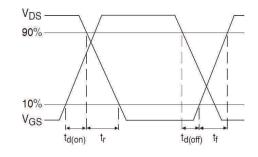


Fig 10b. Switching Time Waveforms

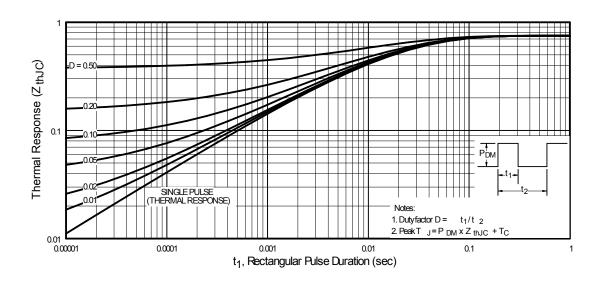


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

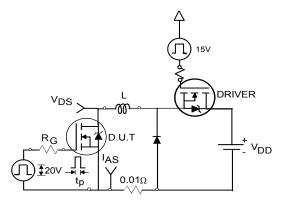


Fig 12a. Unclamped Inductive Test Circuit

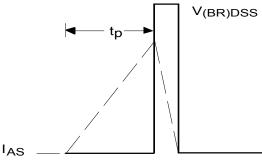
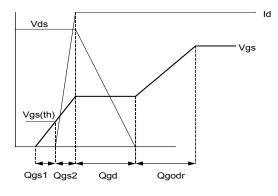
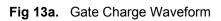


Fig 12b. Unclamped Inductive Waveforms





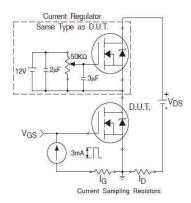


Fig 13b. Gate Charge Test Circuit

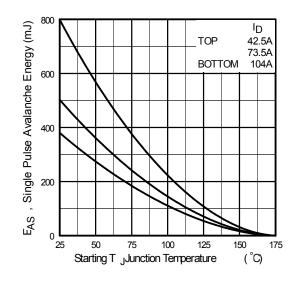


Fig 12c. Maximum Avalanche Energy vs. Drain Current

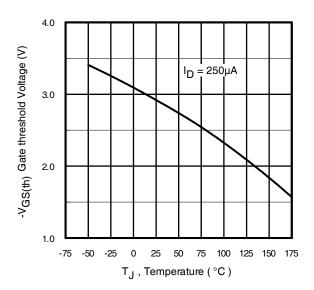


Fig 14. Threshold Voltage vs. Temperature



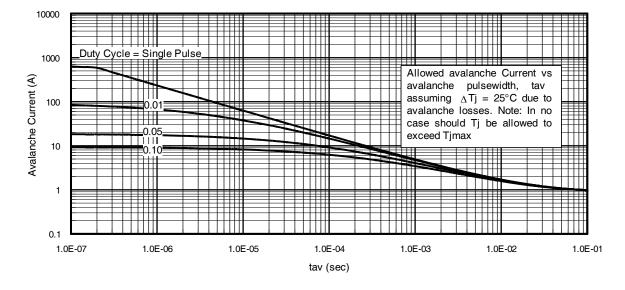
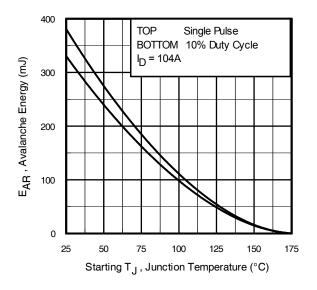
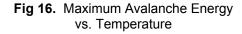


Fig 15. Typical Avalanche Current vs. Pulse width





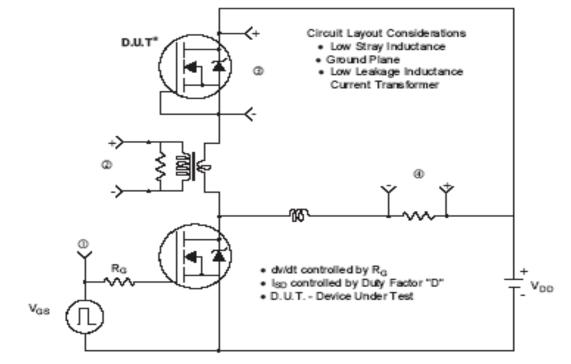
Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).
 - tav = Average time in avalanche.
 - D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

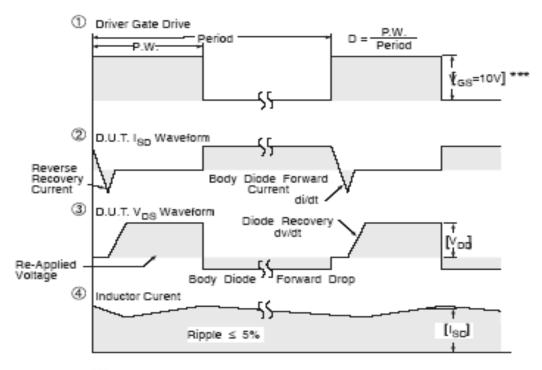
$$\begin{split} \textbf{P}_{D \;(ave)} &= 1/2 \; (\; \textbf{1.3} \cdot \textbf{BV} \cdot \textbf{I}_{av}) = \Delta T / \; \textbf{Z}_{thJC} \\ \textbf{I}_{av} &= 2 \Delta T / \; [\textbf{1.3} \cdot \textbf{BV} \cdot \textbf{Z}_{th}] \\ \textbf{E}_{AS \;(AR)} &= \textbf{P}_{D \;(ave)} \cdot \textbf{t}_{av} \end{split}$$





Peak Diode Recovery dv/dt Test Circuit

* Reverse Polarity of D.U.T for P-Channel



*** VGS = 5.0V for Logic Level and 3V Drive Devices

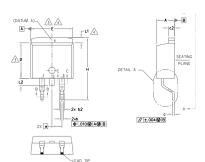
Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



AUIRF2805S/L

D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))

S



PLATIN

1 /4

<u>∕6</u> b1, b3→

-(b b2)

1



1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994

2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.

7. CONTROLLING DIMENSION: INCH.

8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

	S Y M		DIMEN	SIONS		
	В	MILLIM	MILLIMETERS		HES	
	O L	MIN.	MAX.	MIN.	MAX.	
-BASE METAL	A	4.06	4.83	.160	.190	
16	A1	0.00	0.254	.000	.010	
-	b	0.51	0.99	.020	.039	
	Ь1	0.51	0.89	.020	.035	
	b2	1.14	1.78	.045	.070	
	b3	1.14	1.73	.045	.068	
TAIL "A"	С	0.38	0.74	.015	.029	
TED 90° CW CALE 8:1	с1	0.38	0.58	.015	.023	
	c2	1.14	1.65	.045	.065	
PLANE	D	8.38	9.65	.330	.380	
	D1	6.86	_	.270	—	
	E	9.65	10.67	.380	.420	
	E1	6.22	_	.245	—	
	е	2.54	BSC	.100	BSC	
	Н	14.61	15.88	.575	.625	
	L	1.78	2.79	.070	.110	
	L1	_	1.68	_	.066	
	L2	_	1.78	-	.070	
		0.05	DOO	010	000	

LEAD ASSIGNMENTS

NOTES

5

5

5

3

4 3,4 4

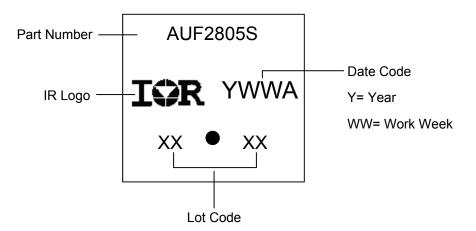
4

DIODES 1.- ANODE (TWO DIE) / OPEN (ONE DIE) 2. 4.- CATHODE 3.- ANODE HEXFET IGBTs, CoPACK 1.- GATE 2, 4.- DRAIN 3.- SOURCE 1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

Ψ SECTION B-B & C-C SCALE: NONE H A-E1-VIEW A-A H DETAIL *A* ROTATED 90° CW SCALE 8:1 GAUGI PLANI B SEATING PLANE . L3–

	1.14	1.00	.045	.005
D	8.38	9.65	.330	.380
D1	6.86	_	.270	_
E	9.65	10.67	.380	.420
Ε1	6.22	_	.245	_
е	2.54	BSC	.100	BSC
Н	14.61	15.88	.575	.625
L	1.78	2.79	.070	.110
L1	_	1.68	_	.066
L2	_	1.78	_	.070
L3	0.25	BSC	.010	BSC

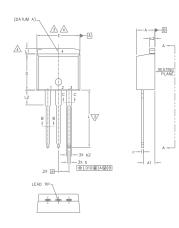
D²Pak (TO-263AB) Part Marking Information

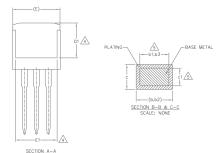




AUIRF2805S/L

TO-262 Package Outline (Dimensions are shown in millimeters (inches)





NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

LEAD ASSIGNMENTS

IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER 4.- COLLECTOR

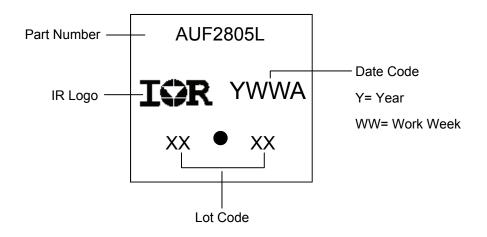
HEXFET DIODES

- 1.- GATE
 - 1.- ANODE (TWO DIE) / OPEN (ONE DIE) 2, 4.- CATHODE 3.- ANODE
- 2.- DRAIN 3.- SOURCE 4.- DRAIN



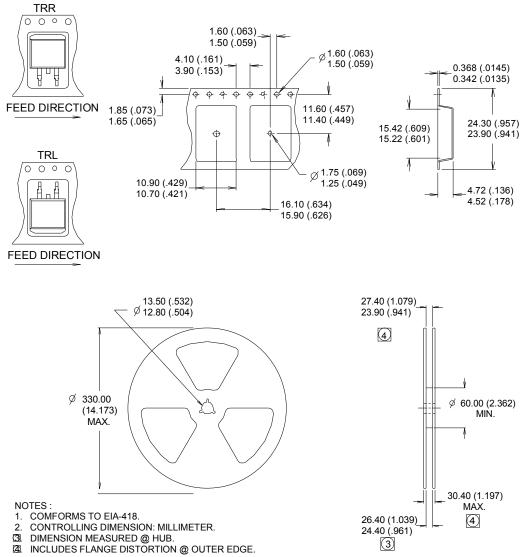
S Y M		N				
B	MILLIMETERS		INC	INCHES		
L	MIN.	MAX.	MIN.	MAX.	O T E S	
A	4.06	4.83	.160	.190		
A1	2.03	3.02	.080	.119		
b	0.51	0.99	.020	.039		
b1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	-	.270	-	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	-	.245		4	
е	2.54	BSC	.100	BSC		
L	13.46	14.10	.530	.555		
L1	_	1.65	-	.065	4	
L2	3.56	3.71	.140	.146		

TO-262 Part Marking Information





D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))



4



Qualification Information

		Automotive (per AEC-Q101)			
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.			
Moisture Sensitivity Level		TO-262 D ² -Pak	MSL1		
		Class M4 (+/- 800V) [†]			
	Machine Model	AEC-Q101-002			
	Liveen Dedy Medel	Class H3A (+/- 5000V) [†]			
ESD	Human Body Model	AEC-Q101-001			
	Charged Device Medel	Class C5 (+/- 2000V) [†]			
	Charged Device Model	AEC-Q101-005			
RoHS Compliant		Yes			

† Highest passing voltage.

Revision History

Date	Comments
9/30/2015	Updated datasheet with corporate template
	Corrected ordering table on page 1.

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